Product data sheet

1. General description

AC Thyristor Triac power switch in a TO263(D2PAK) surface mountable plastic package with self-protective clamping capabilities against low and high energy transients.

2. Features and benefits

- · Clamping structure ensuring safe high over-voltage withstand capability
- · Direct interfacing with low power drivers and microcontrollers
- Full cycle AC conduction
- Over-voltage withstand capability to IEC 61000-4-5
- · Pin compatible with standard triacs
- Planar passivated for voltage ruggedness and reliability
- · Protective self turn-on capability for high energy transients
- · Safe clamping capability for low energy over-voltage transients
- · Sensitive gate for easy logic level triggering
- · Surface mountable package
- Triggering in three quadrants only
- · Very high immunity to false turn-on by dV/dt

3. Applications

- AC fan, pump and compressor controls
- Highly inductive, resistive and safety loads
- Large and small appliances (White Goods)
- · Reversing induction motor controls

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	-	800	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _{mb} ≤ 108 °C; <u>Fig. 1; Fig. 2; Fig. 3</u>	-	-	6	Α
I _{TSM}	non-repetitive peak on- state current	full sine wave; $T_{j(init)}$ = 25 °C; t_p = 20 ms; Fig. 4; Fig. 5	-	-	51	Α
		full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$	-	-	56	Α
T _j	junction temperature		-	-	125	°C
V _{PP}	peak pulse voltage	T _j = 25 °C; non-repetitive; off-state; Fig. 6	-	-	2	kV

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G+;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD- G-;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	10	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 10</u>	-	-	25	mA
V _T	on-state voltage	I _T = 8 A; T _j = 25 °C; <u>Fig. 11</u>	-	-	1.7	V
V _{CL}	clamping voltage	I_{CL} = 0.1 mA; t_p = 1 ms; T_j = 25 °C	850	-	-	V
Dynamic o	haracteristics					
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 13	500	-	-	V/µs
dl _{com} /dt	rate of change of commutating current	$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 6 \text{ A};$ $dV_{com}/dt = 20 \text{ V/}\mu\text{s}; \text{ (snubberless condition)}; \text{ gate open circuit;}$ Fig. 14; Fig. 15	3.5	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 6 \text{ A};$ $dV_{com}/dt = 10 \text{ V}/\mu\text{s}; \text{ gate open circuit};$ Fig. 14; Fig. 15	5	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 6 \text{ A};$ $dV_{com}/dt = 1 \text{ V}/\mu\text{s}; \text{ gate open circuit};$ Fig. 14; Fig. 15	10	-	-	A/ms

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	CM	common		LD
2	LD	load		12X7
3	G	gate		G—ŽV
mb	LD	mounting base; load		CM 003aaf296

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	Package version	Package issue date
ACTT6B-800E	TO263	ACTT6B-800EJ	Reel	800	TO263E	26-May-2017

7. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	800	V
I _{T(RMS)}	RMS on-state current	full sine wave; T _{mb} ≤ 108 °C; Fig. 1; Fig. 2; Fig. 3	-	6	А
I _{TSM}	non-repetitive peak on-state current	full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 20 \text{ ms}$; Fig 4; Fig 5	-	51	A
		full sine wave; $T_{j(init)} = 25 \text{ °C}$; $t_p = 16.7 \text{ ms}$	-	56	А
I ² t	I ² t for fusing	t _p = 10 ms; sine-wave pulse	-	13	A ² s
dl _⊤ /dt	rate of rise of on-state current	I _G = 20 mA	-	100	A/µs
I _{GM}	peak gate current	t _p = 20 μs	-	2	А
P_{GM}	peak gate power		-	5	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.5	W
T _{stg}	storage temperature		-40	150	°C
T _j	junction temperature		-	125	°C
V_{pp}	peak pulse voltage	T _j = 25 °C; non-repetitive, off-state; Fig 6	-	2	kV

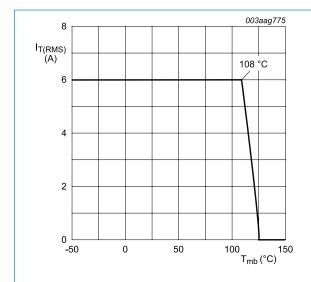
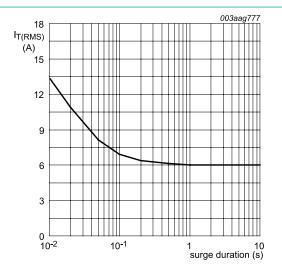
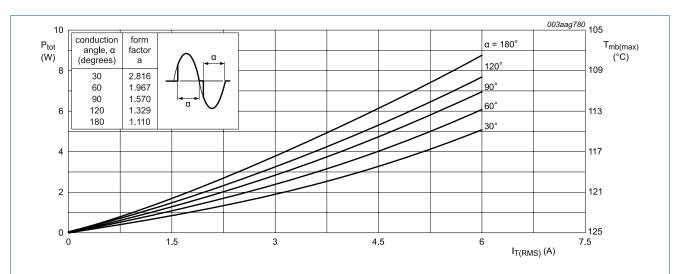


Fig. 1. RMS on-state current as a function of mounting base temperature; maximum values



 $f = 50 \text{ Hz}; T_{mb} = 108 \text{ }^{\circ}\text{C}$

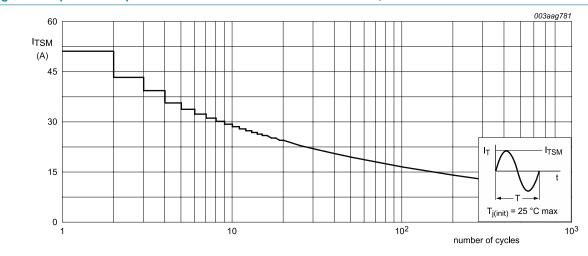
Fig. 2. RMS on-state current as a function of surge duration; maximum values



 α = conduction angle

 $a = form factor = I_{T(RMS)} / I_{T(AV)}$

Fig. 3. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig. 4. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

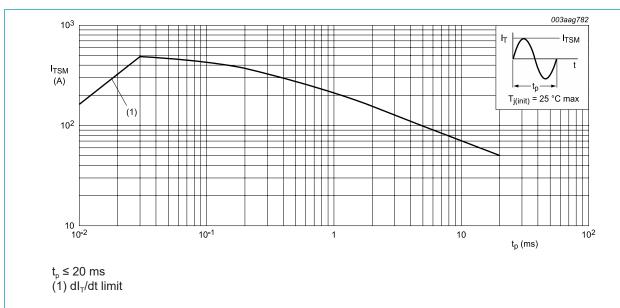


Fig. 5. Non-repetitive peak on-state current as a function of pulse width; maximum values

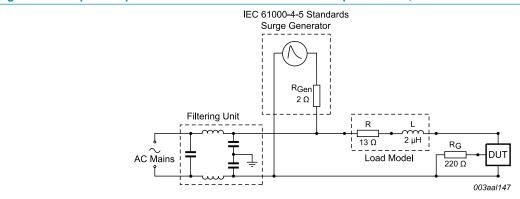
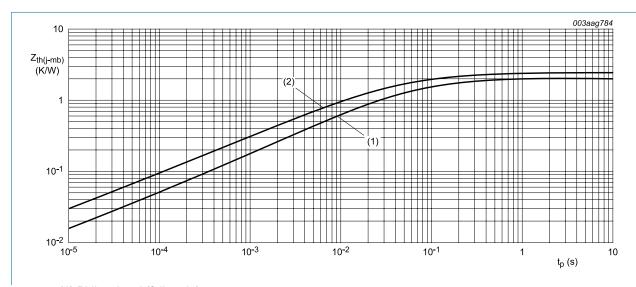


Fig. 6. Test circuit for inductive and resistive loads with conditions equivalent to IEC 61000-4-5

8. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance	full cycle; Fig. 7	-	-	2.4	K/W
	from junction to mounting base	half cycle; <u>Fig. 7</u>	-	-	2	K/W
R _{th(j-a)}	thermal resistance from junction to ambient free air	printed circuit board (FR4) mounted	-	55	-	K/W



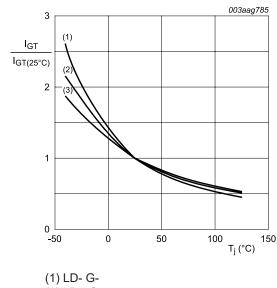
- (1) Bidirectional (full cycle)
- (2) Unidirectional (half cycle)

Fig. 7. Transient thermal impedance from junction to mounting base as a function of pulse width

9. Characteristics

Table 6. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
I _{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G+;}$ $T_j = 25 \text{ °C; } Fig. 8$	-	-	10	mA
		$V_D = 12 \text{ V; } I_T = 100 \text{ mA; LD+ G-;}$ $T_j = 25 ^{\circ}\text{C; } Fig. 8$	-	-	10	mA
		$V_D = 12 \text{ V}; I_T = 100 \text{ mA}; LD- G-;$ $T_j = 25 \text{ °C}; Fig. 8$	-	-	10	mA
l _L	latching current	$V_D = 12 \text{ V}; I_G = 100 \text{ mA}; \text{LD+ G+};$ $T_j = 25 ^{\circ}\text{C}; Fig. 9$	-	-	30	mA
		$V_D = 12 \text{ V}; I_G = 100 \text{ mA}; \text{LD+ G-};$ $T_j = 25 ^{\circ}\text{C}; Fig. 9$	-	-	40	mA
		$V_D = 12 \text{ V}; I_G = 100 \text{ mA}; \text{LD- G-};$ $T_j = 25 ^{\circ}\text{C}; Fig. 9$	-	-	30	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 10</u>	-	-	25	mA
V _T	on-state voltage	I _T = 8 A; T _j = 25 °C; <u>Fig. 11</u>	-	-	1.7	V
V _{GT} (gate trigger voltage	V _D = 12V; I _T = 100 mA;T _j = 25 °C; Fig. 12	-	8.0	1	V
		V _D = 400V; I _T = 100 mA;T _j = 125 °C; Fig. 12	0.2	0.45	-	V
I _D	off-state current	V _D = 800 V; T _j = 25 °C	-	-	10	μΑ
		V _D = 800 V; T _j = 125 °C	-	-	0.5	mA
V _{CL}	clamping voltage	$I_{CL} = 0.1 \text{ mA; } t_p = 1 \text{ ms; } T_j = 25 \text{ °C}$	850	-	-	V
Dynamic	characteristics		•	'	'	
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 536 V; T_j = 125 °C; (V_{DM} = 67% of V_{DRM}); exponential waveform; gate open circuit; Fig. 13	500	-	-	V/µs
dl _{com} /dt	rate of change of commutating current	V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 6 A; dV_{com}/dt = 20 V/ μ s; (snubberless condition); gate open circuit; Fig. 14; Fig. 15	3.5	-	-	A/ms
		V_D = 400 V; T_j = 125 °C; $I_{T(RMS)}$ = 6 A; dV_{com}/dt = 10 V/ μ s; gate open circuit; Fig. 14; Fig. 15	5	-	-	A/ms
		$V_D = 400 \text{ V}; T_j = 125 \text{ °C}; I_{T(RMS)} = 6 \text{ A};$ $dV_{com}/dt = 1 \text{ V}/\mu\text{s}; \text{ gate open circuit};$ Fig. 14; Fig. 15	10	-	-	A/ms





- (2) LD+ G+
- (3) LD+ G-

Fig. 8. Normalized gate trigger current as a function of junction temperature

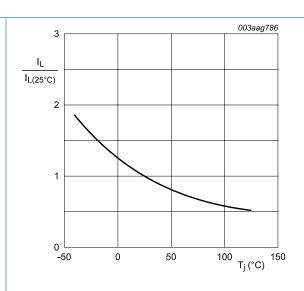


Fig. 9. Normalized latching current as a function of junction temperature

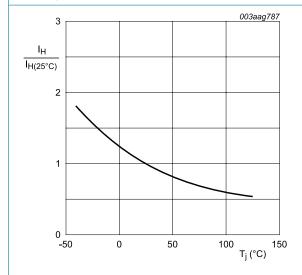
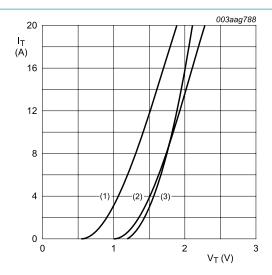


Fig. 10. Normalized holding current as a function of junction temperature



 V_o = 1.109 V; R_s = 0.076 Ω (1) T_j = 125 °C; typical values (2) T_j = 125 °C; maximum values

(3) $T_i = 25$ °C; maximum values

Fig. 11. On-state current as a function of on-state voltage

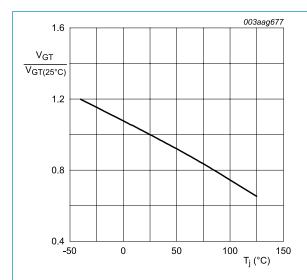
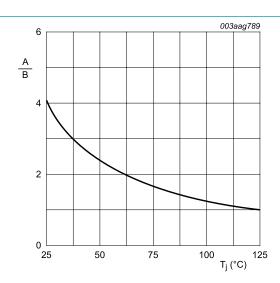
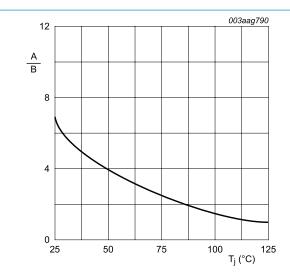


Fig. 12. Normalized gate trigger voltage as a function of junction temperature



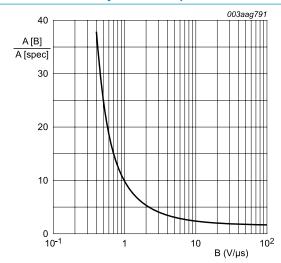
A = dV_D/dt at condition T_j °C B = dV_D/dt at condition T_j [125] °C

Fig. 13. Normalized gate trigger voltage as a function of junction temperature



A = dI_{com}/dt at condition T_j °C B = dI_{com}/dt at condition T_j [125] °C V_D = 400 V

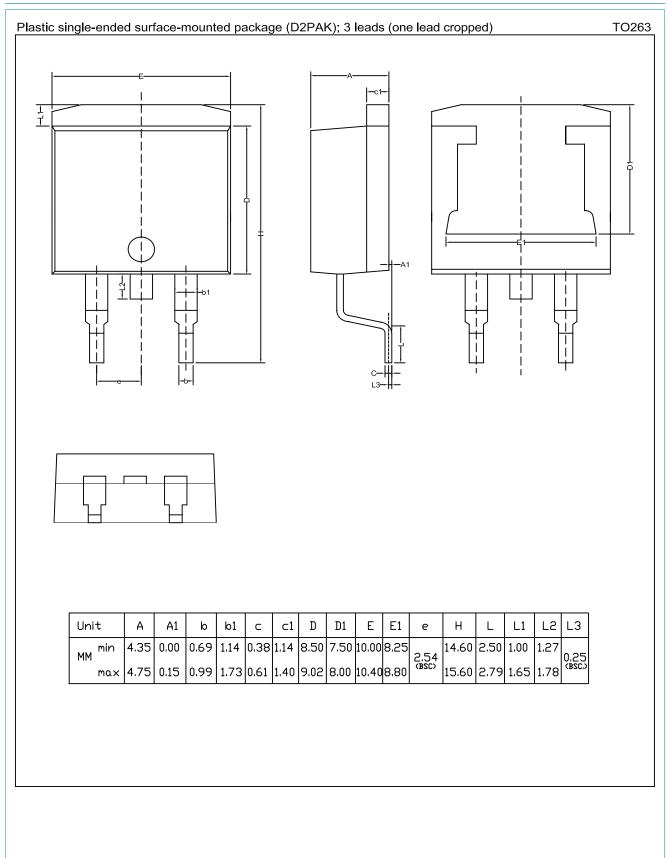
Fig. 12. Normalized critical rate of rise of commutating current as a function of junction temperature



A [B] is dl_{com}/dt at condition B, dV_{com}/dt A [spec] is the specified data sheet value of dl_{com}/dt turn-off time < 20 ms

Fig. 12. Normalized critical rate of change of commutating current as a function of critical rate of change of commutating voltage; minimum values

10. Package outline



11. Legal information

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Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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Date of release: 25 April 2019

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